

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10532830	SHIMADA ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	DAVID CHONG	1797

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
422	98	10/24/08	DC
423	244.1	10/24/08	DC
436	37	10/24/08	DC

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Searched class/subclass narrowed by keyword (see EAST history)	10/21/08	DC
Searched databases USPAT, USPGPUB, USOCR, DERWENT, EPO, and JPO	10/21/08	DC
Consulted with primary examiner Arlen Soderquist	10/21/08	DC
Inventor search in EAST (see EAST history)	10/21/08	DC

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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